Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/609,452	HE ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

SEARCHED					
Class	Subclass	Date	Examiner		
29	592.1 605 830-832 846 854	10/20/2005	PK		
174	52.1 255				
	260 261				
607	1-3 46-52				
	59-61				
600	302 554 377				
127	877	V			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	- 11			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
Text Search EAST/NPL (IEEE)		10/26/2005	PK
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